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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.
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09/407,204 09/28/99 SHEN

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DENVER CO 80265

PAREKH, N

EXAMINER

ART UNIT PAPER NUMBER

2811

DATE MAILED:
07/05/01

Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner of Patents and Trademarks

Office Action Summary

Application No.
09/407,204

Applicant(s)
Shen

Examiner
Nitin Parekh

Art Unit
2811



— The MAILING DATE of this communication appears on the cover sheet with the correspondence address —

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136 (a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on Apr 23, 2001
- 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 35 C.D. 11; 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-6 and 19-21 is/are pending in the application.
- 4a) Of the above, claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-6 and 19-21 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claims _____ are subject to restriction and/or election requirements.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are objected to by the Examiner.
- 11) ☐ The proposed drawing correction filed on _____ is: a) ☐ approved b) ☐ disapproved.
- 12) ☐ The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. § 119

- 13) ☒ Acknowledgement is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d).
- a) ☒ All b) ☐ Some* c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- *See the attached detailed Office action for a list of the certified copies not received.
- 14) ☐ Acknowledgement is made of a claim for domestic priority under 35 U.S.C. § 119(e).

Attachment(s)

- 15) ☒ Notice of References Cited (PTO-892) 18) ☐ Interview Summary (PTO-413) Paper No(s). _____
- 16) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948) 19) ☐ Notice of Informal Patent Application (PTO-152)
- 17) ☐ Information Disclosure Statement(s) (PTO-1449) Paper No(s). _____ 20) ☐ Other: _____

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DETAILED ACTION

Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claims 1-6 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al (US Pat. 6137164) in view of Panchou et al (US Pat. 6040630) and further in view of Bertin et al (US Pat. 5977640).

Regarding claims 1 and 2, Yew et al disclose a semiconductor stacked device/multichip module(MCM) comprising:

- a chip mounting member/printed circuit board-PCB (420 in Fig.4A) having opposite first and second surfaces (Col. 4, line 50), a set of circuit traces and a plurality of conventional vias/plated through holes (430 in Fig. 4A) that extend through the first and second surfaces and are connected to the circuit traces
- a first and second semiconductor chips (401/402 in Fig. 4A) on top and bottom surfaces of the PCB respectively and the semiconductor chips having a pad mounting surface with a plurality of contact pads/terminals (411 in Fig. 4A) provided thereon

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- a first and second conductor units including a plurality of conventional conductive contact bumps/terminals (412 in Fig. 4A; Col. 4, line 55) for electrically connecting the contact pads of the first semiconductor chip and first circuit traces, and
- plurality of solder balls/external connections (440 in Fig. 4A) disposed on one of the surfaces of the chip mounting member

(Fig. 4A; Col. 4, line 50- Col. 7, line 2).

Yew et al disclose the first semiconductor chip being conventionally bonded to the chip mounting member/PCB using flip-chip bonding of the conductive balls/bumps (Col. 7, line 6) but fails to specify using a first dielectric tape for bonding/securing adhesively with the a plurality of holes at positions registered with the first conductor unit including a plurality contact pads/balls of the first semiconductor chip to bond and establish the electrical connection between the chip to the first circuit traces on the chip mounting member/substrate and aligning/connecting solder balls to the respective plated through holes. Panchou et al teach using a conventional attachment film/dielectric tape with a plurality of holes at positions in registration with the corresponding contact pads/balls of the chip in adhesive bonding of a flip chip device (Fig. 4 and 4a; Col. 5; Fig. 1-4). The cited reference by Clayton teaches using the conventional adhesive film/dielectric tape for bonding the first and second semiconductor chips on the circuit substrate (Fig. 18A-D; Col.. 11, line 36; Col. 18, line 50) in a multichip module with wire bonding (Fig. 18C) or flip chip bonding (Fig. 18D). Clayton further teaches disposing the first circuit traces and the first semiconductor chip on the same surface of the chip mounting member/substrate and

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forming the bonding with the contact pads/balls being registered with those of the chip and the substrate (74 and 76 in Fig. 18D; Col. 19, line 33) in flip chip. Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to use a first dielectric tape for bonding/securing adhesively with a plurality of holes at positions registered with the first conductor unit including a plurality contact pads/balls of the first semiconductor chip to bond and establish the electrical connection between the chip to the first circuit traces on the chip mounting member/substrate to improve the chip bonding using Panchou et al's bonding tape in Yew et al's MCM.

Regarding claims 3 and 4, Yew et al fail to specify using a second dielectric tape with a plurality of holes at positions registered with the plurality of balls of the second semiconductor chip to bond and establish the electrical connection between the second semiconductor chip to the second circuit traces on chip mounting member/substrate. However, as explained above for claims 1 and 2, Yew et al in view of Panchou et al further teach using the second semiconductor chip, second dielectric tape with a plurality of holes and the second conductor unit including plurality of conductive pads/balls in registration with the corresponding holes in the tape. Therefore, claims 3 and 4 are rejected as explained above for claims 1 and 2.

Regarding claim 5, Yew et al disclose providing a polymer resin/epoxy (Fig. 4A; Col. 6, line 27) on the bottom peripheral portion to strengthen the bonding of the first semiconductor chip with

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the same one of the surfaces of the chip mounting member/PCB but fails to specify using resin on the peripheral side portion of the chip. The cited references by Tanioka (Fig. A) and Egawa (resin 22 in Fig. 2; Col. 4) teach using conventional epoxy/resin on the peripheral/side portion to strengthen the bonding of the first semiconductor chip. Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to provide an epoxy resin on the peripheral side portion of the chip to strengthen the bonding of the first semiconductor chip with the same one of the surfaces of the chip mounting member/PCB in Yew et al's MCM.

Regarding claim 6, Yew et al in view of Panchou et al fail to specify securing a heat dissipating plate on the heat dissipating surface opposite to the pad mounting surface of the chip. Bertin et al teach using conventional heat spreader/plate secured on the heat dissipating surface opposite to the pad mounting surface of the chip (Fig. 7 and 15; Col. 4, line 16) to improve heat dissipation. Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate a heat dissipating plate on the heat dissipating surface opposite to the pad mounting surface of the chip to improve heat dissipation using Bertin et al's heat spreader in Yew et al's module in view of Panchou et al.

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3. Claim 19 is rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al (US Pat. 6137164) in view of Panchou et al (US Pat. 6040630) and further in view of Akram et al (US Pat. 6051878).

As explained above for claims 1-4, Yew et al in view of Panchou et al teach using a MCM including all elements of the claim 19 except using a stack comprising upper and lower semiconductor chip modules. Akram et al teach using conventional stacking of two identical semiconductor chip modules using alignment of respective external pin or solder ball connections (Fig.1; Col. 4, line 36-57) of upper and lower modules to form a multiple stack. The cited reference by Londa teach using the solder balls/bumps aligned to the respective plated through holes extending through upper and lower surfaces of each module and connecting the two modules (10 and 10' in Fig. 2) to form a stacked semiconductor chip module comprising upper and lower semiconductor chip (Col. 4). Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate a stack comprising upper and lower semiconductor chip modules such that the solder balls/bumps aligned to the respective plated through holes of each module to achieve multi-level connection capability using Akram's stack layout in Yew et al's MCM in view of Panchou et al.

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4. Claims 20 and 21 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al (US Pat. 6137164) in view of Panchou et al (US Pat. 6040630) as explained above for claims 1-4.

Response to Arguments

5. Applicant's arguments with respect to claims 1-6 and 19 have been considered but are moot in view of the new ground(s) of rejection.

Papers related to this application may be submitted directly to Art Unit 2811 by facsimile transmission. Papers should be faxed to Art Unit via Technology Center 2800 fax center located in Crystal Plaza 4, room 4C23. The faxing of such papers must conform with the notice published in the Official Gazette, 1096 OG 30 (15 November 1989).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nitin Parekh whose telephone number is (703) 305-3410. The examiner can be normally reached on Monday-Friday from 08:30 am-5:00 pm.

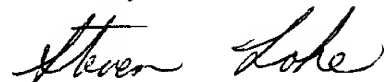
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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tom Thomas, can be reached on (703) 308-2772. The fax number for the organization where this application or proceeding is assigned is (703) 308-7722 or 7724.

Nitin Parekh

06-29-01

Steven Loke
Primary Examiner

A handwritten signature in cursive script that reads "Steven Loke".